

**Search Notes**

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

MURCIA ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
347	22-24,28 29,30,32 33,35	3/22/2006	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR